Notice of References Cited Application/Control No. 10/576,055 Examiner DAVID X. YI Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | Α | US-2008/0052748 | 02-2008 | Pei et al. | 725/088 |
| * | В | US-7,130,912 | 10-2006 | Nishikado et al. | 709/229 |
| * | C | US-2005/0262258 | 11-2005 | Kohno et al. | 709/231 |
| * | D | US-2005/0102427 | 05-2005 | Yokota et al. | 709/245 |
| * | Е | US-2004/0019749 | 01-2004 | Mochida et al. | 711/151 |
| * | F | US-7,274,712 | 09-2007 | Wong et al. | 370/486 |
| * | G | US-6,662,230 | 12-2003 | Eichstaedt et al. | 709/229 |
| | Ι | US- | | | |
| | - | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | Ø | | | | | |
| | R | | | | | |
| | Ø | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | ٧ | |
| | w | |
| | x | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.